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# **Electromagnetic Imaging from Radio Frequency to Sub-millimeter**Waves

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# **Message from the Guest Editors**

The objective of electromagnetic imaging is to retrieve information about tested structures by studying their interactions with electromagnetic waves. To make a long story short, this involves solving an inverse problem, where the measurable effect is a field-related quantity, and the cause is related to the targets' geometric and electromagnetic properties. The major benefit of using non-ionizing radiation for electromagnetic imaging is the possibility of acquiring target features and analyzing objects in a fully non-invasive and safe way.

Topics of interest include, but are not limited to:

- Electromagnetic imaging
- Microwave imaging
- Millimeter-Wave imaging
- THz imaging
- Tomography
- Inverse scattering
- Inverse problems
- Subsurface imaging
- Nondestructive tests
- Through-the-Wall imaging
- Biomedical diagnostics
- Security imaging











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# **Message from the Editor-in-Chief**

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